

# The SPEM@MAX-lab: Microspectroscopy results on layered materials

D. Rahn<sup>1</sup>, M. Källäne<sup>1</sup>, H. Starnberg<sup>2</sup>, E. Ludwig<sup>1</sup>, A. Zakharov<sup>3</sup>, J. Buck<sup>1</sup>, U. Johannson<sup>3</sup>, L. Kipp<sup>1</sup>,  
and  
K. Rossnagel<sup>1</sup>

<sup>1</sup>*Institute for Experimental and Applied Physics, University Kiel, Germany*

<sup>2</sup>*Department of Physics, Göteborg University, SE-41296 Göteborg, Sweden*

<sup>3</sup>*MAX-lab, SE-22100 Lund, Sweden*

Since the first photoelectron spectroscopy experiments by Siegbahn [1] and Turner [2] the method has passed through an outstanding symbiotic process of technical improvements and new experimental possibilities and approaches. In recent years a lot of work focussed on pushing the method to its very limits. Beside the refinement of energy resolution, the invention of parallel angle detection, the achievement of temperatures below 1 K and the filming of photoelectrons with time resolutions in the range of a few femtoseconds in particular spatial information about photoelectrons is getting more and more in the focus of developments.

The SPEM at MAX-lab, designed in the late 1990's by Johannson [3] at the undulator Beamline BL 31, provides unique focussing properties. After passing through two prefocussing mirrors in the well known Kirkpatrick-Baez configuration and through an ellipsoidal mirror the synchrotron light is focussed to a spot size of 1.5  $\mu\text{m}$  for an available photon energy range of 15 eV to 170 eV. A VG CLAM 2 analysator at a fixed angle of 47.5° enables the detection of photoelectrons with an overall energy resolution below  $\Delta E = 100$  meV which makes this experiment a powerful tool to study the chemical composition of micro-structured materials.

To demonstrate the performance of this old, but for chemical contrast imaging still well-suited machine, we present data on different micro-structured layered materials [4] and compare the results to measurements obtained at recently new developed SPEM instruments at the ALS and Elettra.

## References

- [1] C. Nordling, E. Sokolowski, and K. Siegbahn, *Phys. Rev.* **105**, 1676 (1957).
- [2] D. W. Turner, M. I. Al Jobory, *J. Chem. Phys.* **37**, 3007 (1962).
- [3] U. Johannson, *Vacuum Ultraviolet Scanning Photoelectron Microscopy*, PhD Thesis (1997).
- [4] M. Källäne, K. Rossnagel, M. Marczynski-Bühlow, H. I. Starnberg, S. E. Stoltz, and L. Kipp, *Phys. Rev. Lett.* **100**, 065502 (2008).